DISCRETE SEMICONDUCTORS

DATA SHEET

BF1212; BF1212R; BF1212WR N-channel dual-gate MOS-FETs

Product specification

2003 Nov 14



N-channel dual-gate MOS-FETs

BF1212; BF1212R; BF1212WR

FEATURES

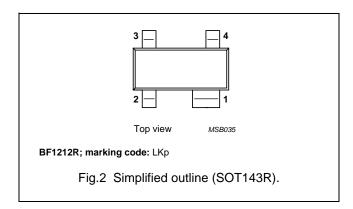
- Short channel transistor with high forward transfer admittance to input capacitance ratio
- · Low noise gain controlled amplifier
- Excellent low frequency noise performance
- Partly internal self-biasing circuit to ensure good cross-modulation performance during AGC and good DC stabilization.

APPLICATIONS

 Gain controlled low noise VHF and UHF amplifiers for 5 V digital and analog television tuner applications.

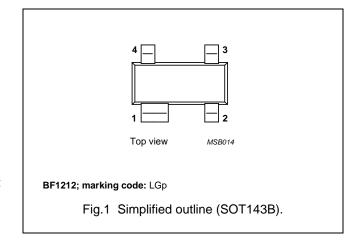
DESCRIPTION

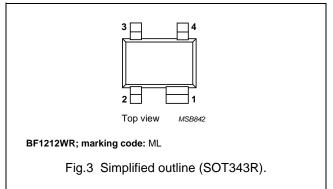
Enhancement type N-channel field-effect transistor with source and substrate interconnected. Integrated diodes between gates and source protect against excessive input voltage surges. The BF1212, BF1212R and BF1212WR are encapsulated in the SOT143B, SOT143R and SOT343R plastic packages respectively.



PINNING

PIN	DESCRIPTION
1	source
2	drain
3	gate 2
4	gate 1





QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V _{DS}	drain-source voltage		_	_	6	V
I _D	drain current		-	_	30	mA
P _{tot}	total power dissipation		-	_	180	mW
y _{fs}	forward transfer admittance		28	33	43	mS
C _{ig1-ss}	input capacitance at gate 1		-	1.7	2.2	pF
C _{rss}	reverse transfer capacitance	f = 1 MHz	-	15	30	fF
F	noise figure	f = 800 MHz	-	1.1	1.8	dB
X _{mod}	cross-modulation	input level for k = 1 % at 40 dB AGC	100	104	_	dBμV
Tj	junction temperature		_	_	150	°C

N-channel dual-gate MOS-FETs

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CAUTION

This product is supplied in anti-static packing to prevent damage caused by electrostatic discharge during transport and handling.

ORDERING INFORMATION

TYPE NUMBER		PACKAGE				
ITPE NUMBER	NAME	DESCRIPTION	VERSION			
BF1212	_	plastic surface mounted package; 4 leads	SOT143B			
BF1212R	_	plastic surface mounted package; reverse pinning; 4 leads	SOT143R			
BF1212WR	_	plastic surface mounted package; reverse pinning; 4 leads	SOT343R			

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{DS}	drain-source voltage		_	6	V
I _D	drain current (DC)		_	30	mA
I _{G1}	gate 1 current		_	±10	mA
I _{G2}	gate 2 current		_	±10	mA
P _{tot}	total power dissipation				
	BF1212; BF1212R	T _s ≤ 116 °C; note 1	_	180	mW
	BF1212WR	T _s ≤ 122 °C; note 1	_	180	mW
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		_	150	°C

Note

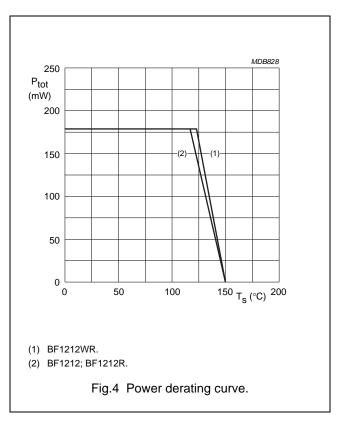
THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	VALUE	UNIT
R _{th j-s}	thermal resistance from junction to soldering point		
	BF1212; BF1212R	185	K/W
	BF1212WR	155	K/W

^{1.} T_s is the temperature of the soldering point of the source lead.

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STATIC CHARACTERISTICS

 $T_j = 25$ °C unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{(BR)DSS}	drain-source breakdown voltage	$V_{G1-S} = V_{G2-S} = 0 \text{ V}; I_D = 10 \mu\text{A}$	6	_	V
V _{(BR)G1-SS}	gate 1-source breakdown voltage	$V_{G2-S} = V_{DS} = 0 \text{ V; } I_{G1-S} = 10 \text{ mA}$	6	10	٧
V _{(BR)G2-SS}	gate 2-source breakdown voltage	$V_{G1-S} = V_{DS} = 0 \text{ V}; I_{G2-S} = 10 \text{ mA}$	6	10	٧
V _{(F)S-G1}	forward source-gate 1 voltage	$V_{G2-S} = V_{DS} = 0 \text{ V}; I_{S-G1} = 10 \text{ mA}$	0.5	1.5	٧
V _{(F)S-G2}	forward source-gate 2 voltage	$V_{G1-S} = V_{DS} = 0 \text{ V}; I_{S-G2} = 10 \text{ mA}$	0.5	1.5	٧
V _{G1-S(th)}	gate 1-source threshold voltage	$V_{G2-S} = 4 \text{ V}; V_{DS} = 5 \text{ V}; I_D = 100 \mu\text{A}$	0.3	1.0	٧
V _{G2-S(th)}	gate 2-source threshold voltage	$V_{G1-S} = 5 \text{ V}; V_{DS} = 5 \text{ V}; I_D = 100 \mu\text{A}$	0.35	1.0	٧
I _{DSX}	drain-source current	$V_{G2-S} = 4 \text{ V}; V_{DS} = 5 \text{ V}; R_{G1} = 150 \text{ k}\Omega;$ note 1	8	16	mA
I _{G1-S}	gate 1 cut-off current	$V_{G2-S} = V_{DS} = 0 \text{ V}; V_{G1-S} = 5 \text{ V}$	_	50	nA
I _{G2-S}	gate 2 cut-off current	V _{G1-S} = V _{DS} = 0 V; V _{G2-S} = 4 V	_	20	nA

Note

1. R_{G1} connects G_1 to $V_{GG} = 5$ V.

N-channel dual-gate MOS-FETs

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DYNAMIC CHARACTERISTICS

Common source; T_{amb} = 25 °C; V_{G2-S} = 4 V; V_{DS} = 5 V; I_D = 12 mA; unless otherwise specified.

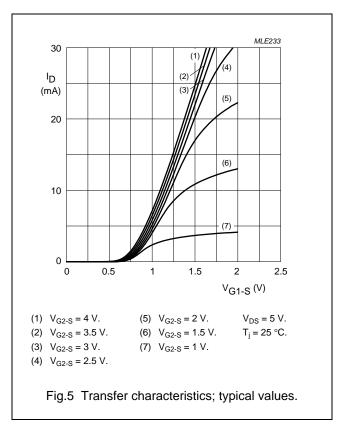
SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
y _{fs}	forward transfer admittance	pulsed; T _j = 25 °C	28	33	43	mS
C _{ig1-ss}	input capacitance at gate 1	f = 1 MHz	-	1.7	2.2	pF
C _{ig2-ss}	input capacitance at gate 2	f = 1 MHz	-	1.1	-	pF
C _{oss}	output capacitance	f = 1 MHz	_	0.9	_	pF
C _{rss}	reverse transfer capacitance	f = 1 MHz	-	15	30	fF
F	noise figure	$f = 11 \text{ MHz}; G_S = 20 \text{ mS}; B_S = 0$	-	4	-	dB
		$f = 400 \text{ MHz}; Y_S = Y_{S \text{ (opt)}}$	-	0.9	1.6	dB
		f = 800 MHz; Y _S = Y _{S (opt)}	_	1.1	1.8	dB
G _{tr}	power gain	$f = 200 \text{ MHz}; G_S = 2 \text{ mS}; B_S = B_{S \text{ (opt)}};$	_	35	_	dB
		$G_L = 0.5 \text{ mS}; B_L = B_{L \text{ (opt)}}$				
		$f = 400 \text{ MHz}; G_S = 2 \text{ mS}; B_S = B_{S \text{ (opt)}};$	_	30	_	dB
		$G_L = 1 \text{ mS}; B_L = B_{L \text{ (opt)}}$				
		$f = 800 \text{ MHz}; G_S = 3.3 \text{ mS}; B_S = B_{S \text{ (opt)}};$	_	25	_	dB
		$G_L = 1 \text{ mS}; B_L = B_{L \text{ (opt)}}$				
X_{mod}	cross-modulation	input level for k = 1%; f _w = 50 MHz;				
		f _{unw} = 60 MHz; note 1				
		at 0 dB AGC	90	_	_	dBμV
		at 10 dB AGC	-	89	_	dBμV
		at 40 dB AGC	100	104	_	dBμV

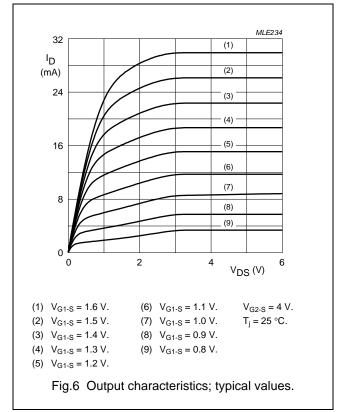
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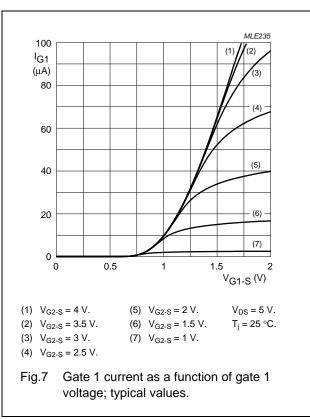
1. Measured in test circuit Fig.21.

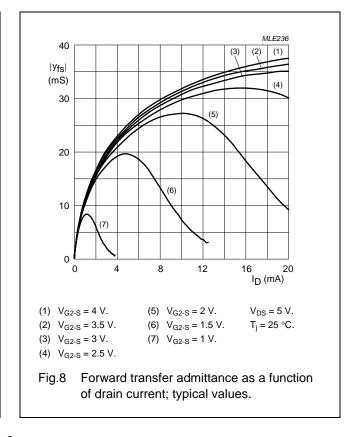
N-channel dual-gate MOS-FETs

BF1212; BF1212R; BF1212WR









N-channel dual-gate MOS-FETs

BF1212; BF1212R; BF1212WR

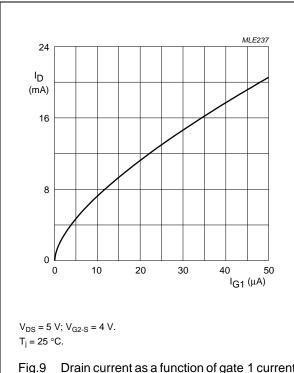
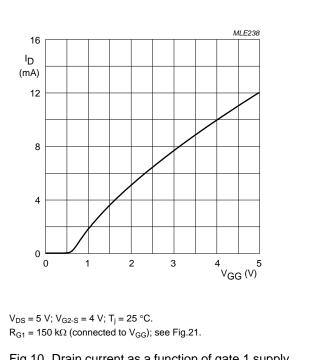
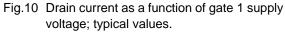
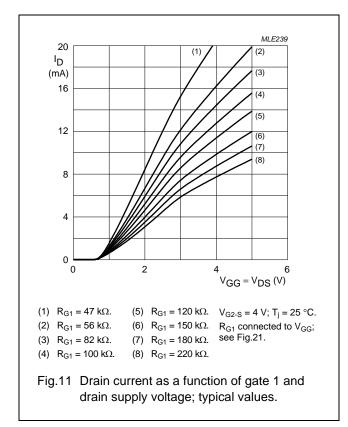
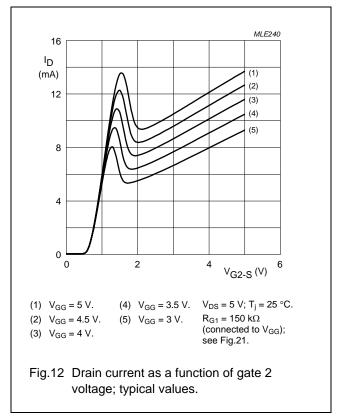


Fig.9 Drain current as a function of gate 1 current; typical values.



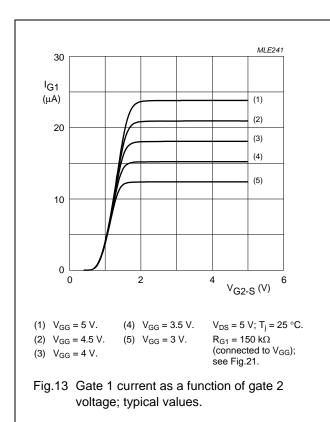






N-channel dual-gate MOS-FETs

BF1212; BF1212R; BF1212WR



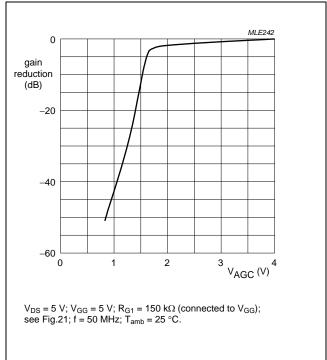
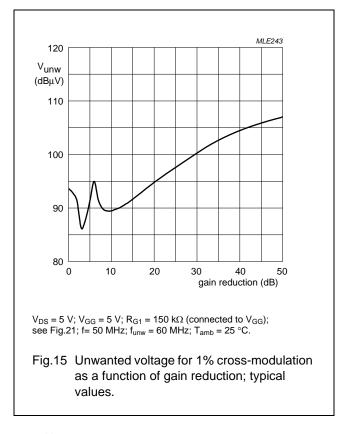
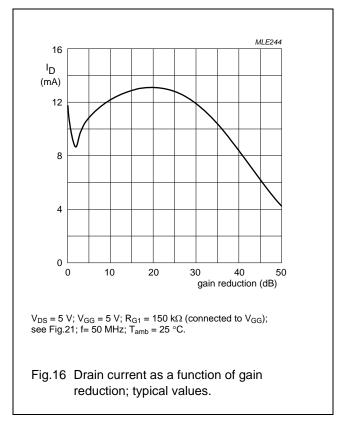


Fig.14 Typical gain reduction as a function of AGC voltage.





N-channel dual-gate MOS-FETs

BF1212; BF1212R; BF1212WR

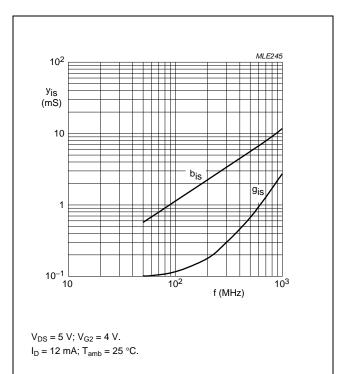


Fig.17 Input admittance as a function of frequency; typical values.

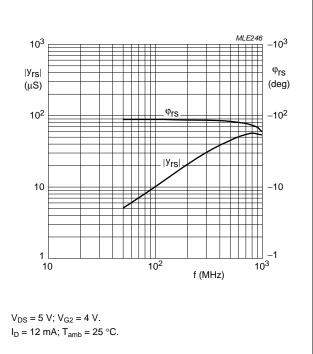


Fig.18 Reverse transfer admittance and phase as functions of frequency; typical values.

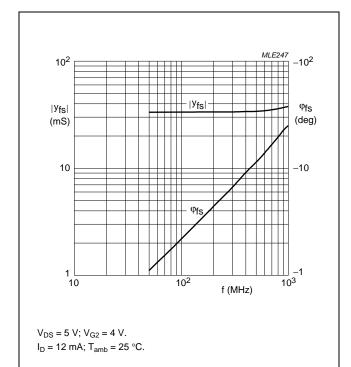
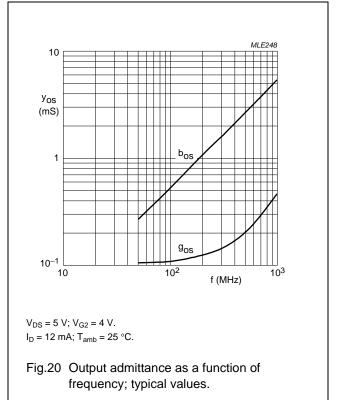


Fig.19 Forward transfer admittance and phase as functions of frequency; typical values.



N-channel dual-gate MOS-FETs

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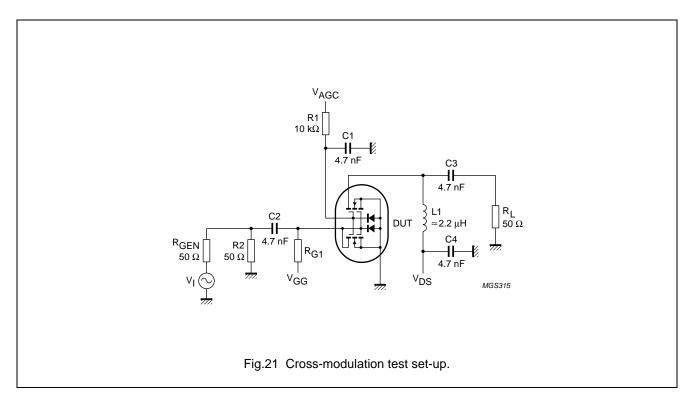


Table 1 Scattering parameters: $V_{DS} = 5 \text{ V}$; $V_{G2-S} = 4 \text{ V}$; $I_D = 12 \text{ mA}$; $T_{amb} = 25 ^{\circ}\text{C}$

	3 7 and 5 5 7 62 6 7 62 6 7 6 7 6 7 6 7 6 7 6 7 6 7									
f	s ₁₁		s ₂₁		s ₁₂		s ₂₂			
(MHz)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)		
50	0.990	-3.39	3.288	176.5	0.0005	86.9	0.990	-1.66		
100	0.988	-6.76	3.280	173.0	0.0011	85.6	0.990	-3.30		
200	0.983	-13.40	3.261	166.1	0.0021	81.2	0.991	-6.62		
300	0.974	-19.86	3.218	159.0	0.0030	77.5	0.991	-9.92		
400	0.969	-26.46	3.205	152.6	0.0039	74.6	0.994	-13.30		
500	0.958	-32.73	3.141	145.9	0.0045	72.4	0.994	-16.56		
600	0.947	-38.83	3.086	139.5	0.0049	70.9	0.993	-19.77		
700	0.936	-44.75	3.017	133.1	0.0051	69.5	0.991	-22.78		
800	0.924	-50.51	2.949	126.9	0.0051	69.9	0.981	-25.77		
900	0.910	-56.18	2.870	120.5	0.0049	69.8	0.984	-28.72		
1000	0.896	-61.64	2.785	114.7	0.0045	72.7	0.980	-31.77		

Table 2 Noise data: V_{DS} = 5 V; $V_{G2\text{-}S}$ = 4 V; I_D = 12 mA; T_{amb} = 25 °C

f	F _{min}	Γ	opt	R _n
(MHz)	(dB)	(ratio)	(deg)	(Ω)
400	0.9	0.695	13.87	28.5
800	1.1	0.634	30.30	32.85

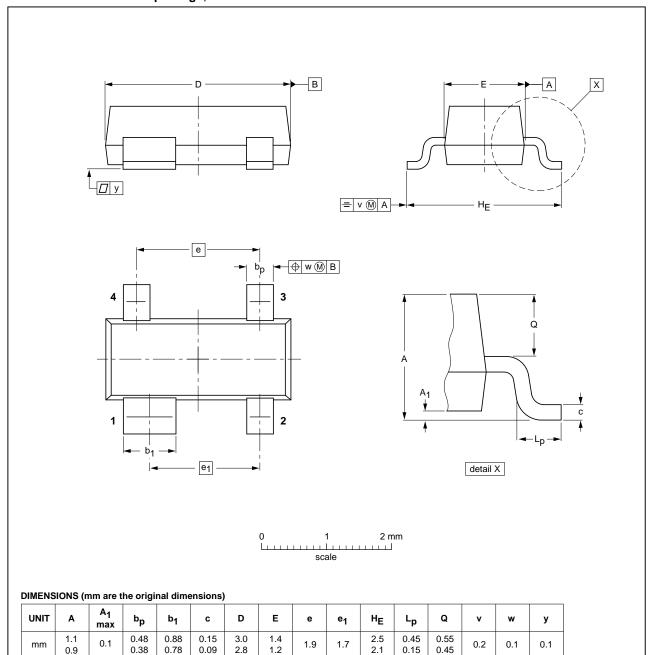
N-channel dual-gate MOS-FETs

BF1212; BF1212R; BF1212WR

PACKAGE OUTLINES

Plastic surface-mounted package; 4 leads

SOT143B



OUTLINE	REF		REFERENCES EUROPEAN		REFERENCES		EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE		
SOT143B					$ \ \ $	04-11-16 06-03-16		

N-channel dual-gate MOS-FETs

BF1212; BF1212R; BF1212WR

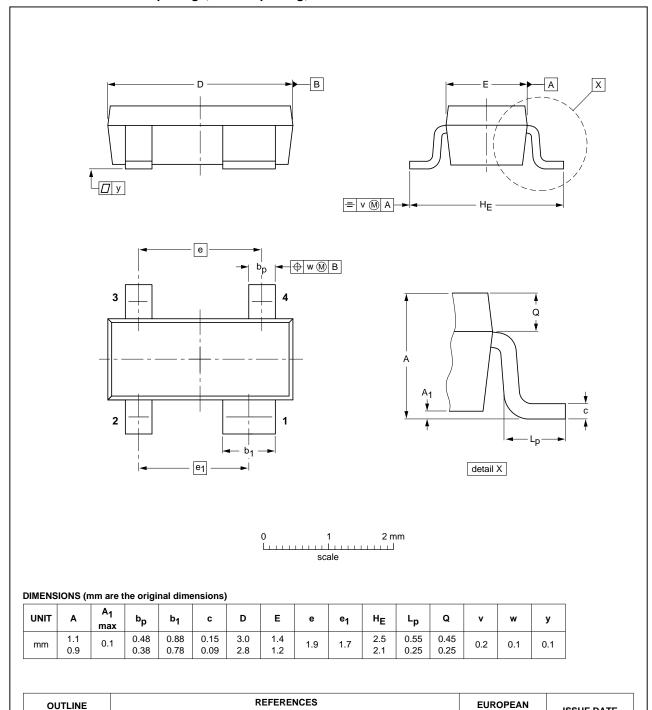
Plastic surface-mounted package; reverse pinning; 4 leads

SOT143R

ISSUE DATE

04-11-16 06-03-16

PROJECTION



JEITA

SC-61AA

12

IEC

JEDEC

VERSION

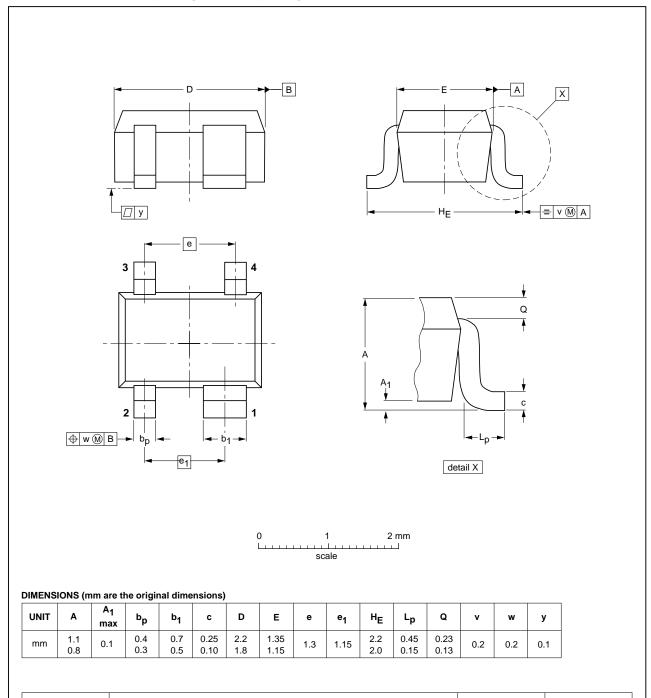
SOT143R

N-channel dual-gate MOS-FETs

BF1212; BF1212R; BF1212WR

Plastic surface-mounted package; reverse pinning; 4 leads

SOT343R



OUTLINE	REFERENCES			EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ		PROJECTION	1990E DATE
SOT343R						97-05-21 06-03-16
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N-channel dual-gate MOS-FETs

BF1212; BF1212R; BF1212WR

DATA SHEET STATUS

DOCUMENT STATUS ⁽¹⁾	PRODUCT STATUS ⁽²⁾	DEFINITION
Objective data sheet	Development	This document contains data from the objective specification for product development.
Preliminary data sheet	Qualification	This document contains data from the preliminary specification.
Product data sheet	Production	This document contains the product specification.

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